



July 11, 2022 | AKI FUJIMURA, CEO, D2S, Inc.

# Is Curvy Design an Opportunity, or a Dream?

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# Today's GPU Workstation = 8,000 Cray-2s

60,000,000x Price Performance

*It's time to rethink EDA*



Cray-2 (1985)

1.9 GFLOPS w/500MB @ \$15M



nVIDIA RTX 3090 Ti (2021)

15,300 GFLOPS w/24GB @ \$2,000

# Computation Choices Impact Execution Choices

Today's Semiconductor Design Choices



Minecraft, Mojang (Microsoft)

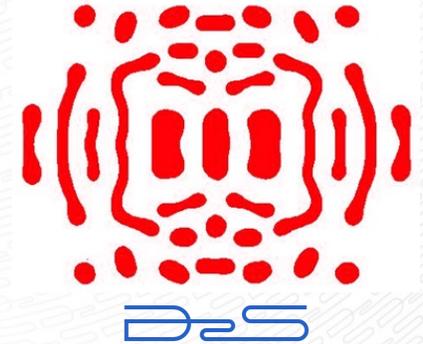
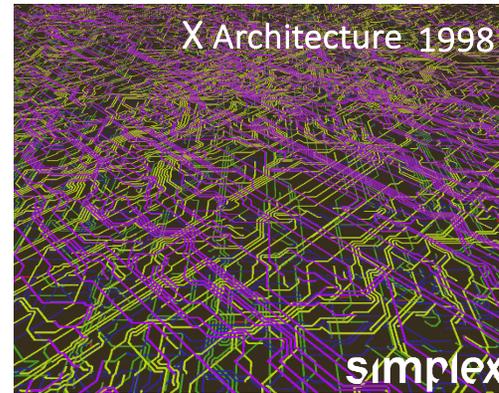
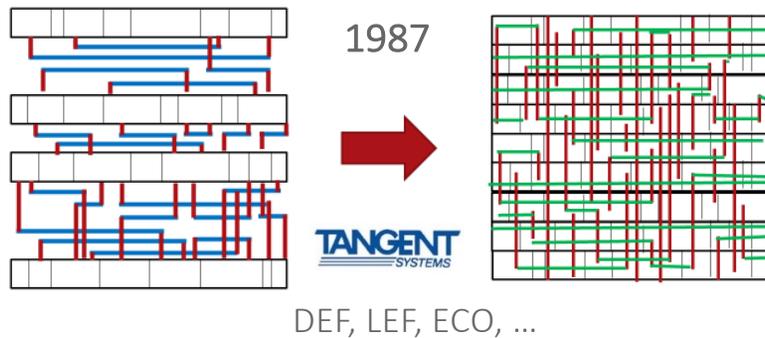
The Future Semiconductor Design Could Choose Now



Death Stranding, Kojima Productions



# Once Upon a Time, Rectangles Served a Purpose



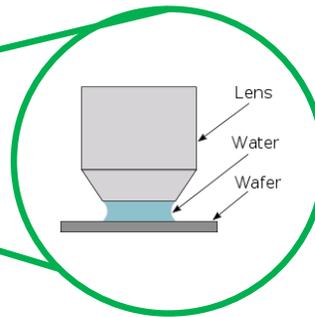
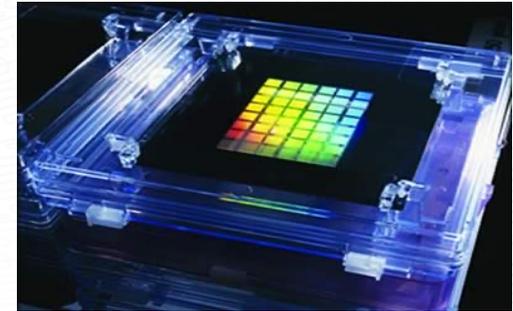
Edge-based, Manhattan design assumptions made design easier, and most importantly, were a practical fit for the computation available at the time

**But times (and computing) have changed...**

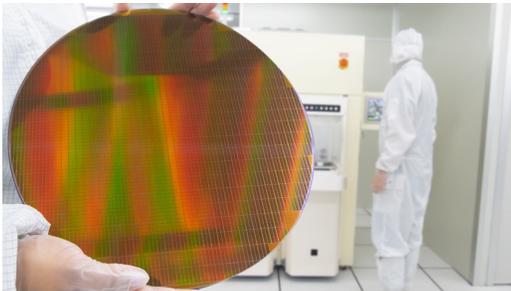
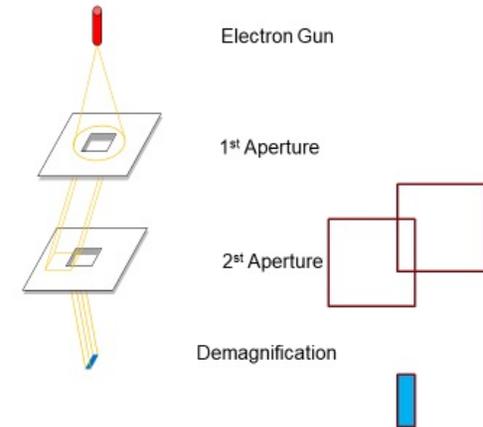
# Wafers are Exposed by Masks



photomask



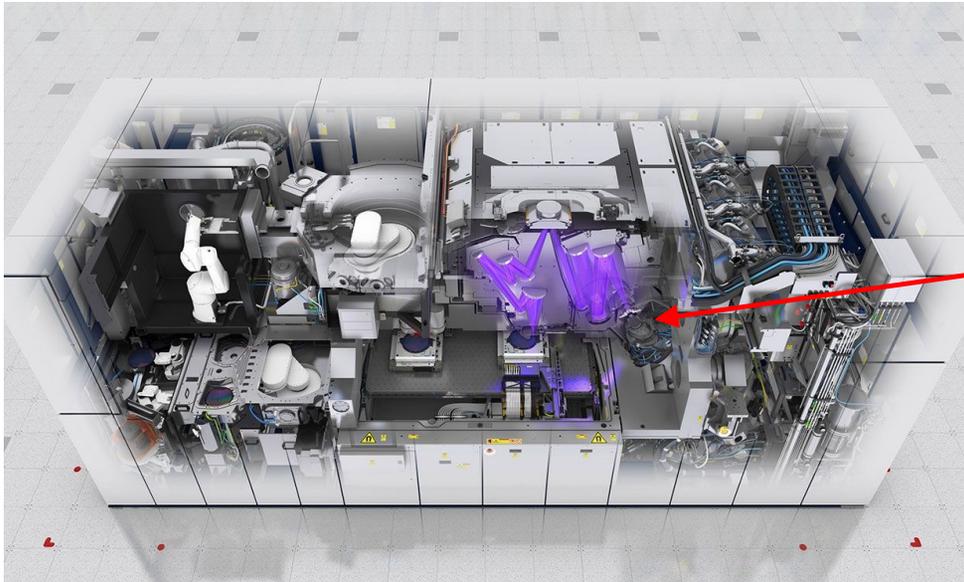
Variable Shaped Beam (VSB) Mask Writing



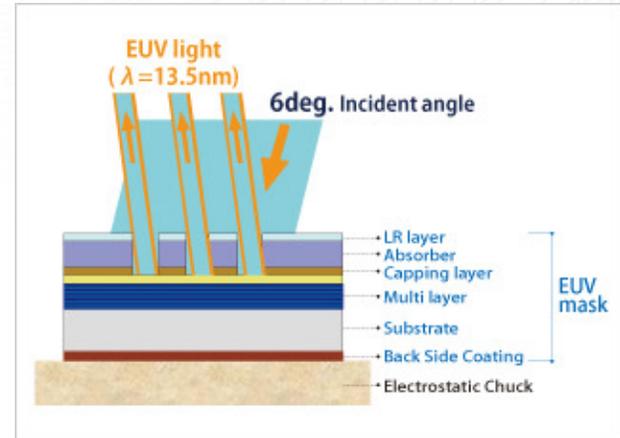
Resolution of 193i =  
$$\frac{193\text{nm wavelength}}{1.35 \text{ Numerical Aperture}}$$



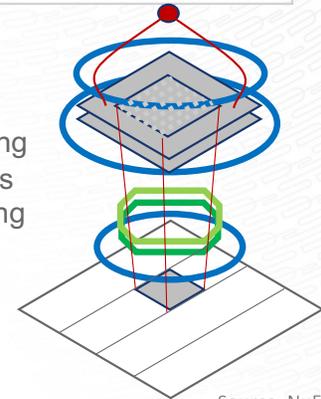
# EUV: Still Wafers are Exposed by Masks



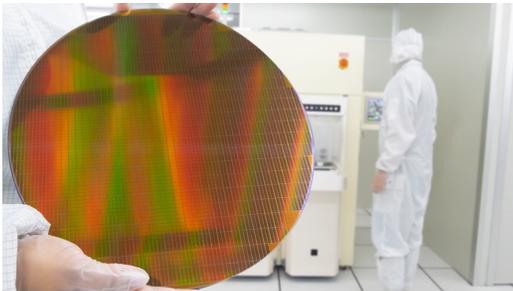
EUV mask



Multi-Beam Mask Writing  
256K square apertures  
for electron beam writing  
of masks



Source: NuFlare

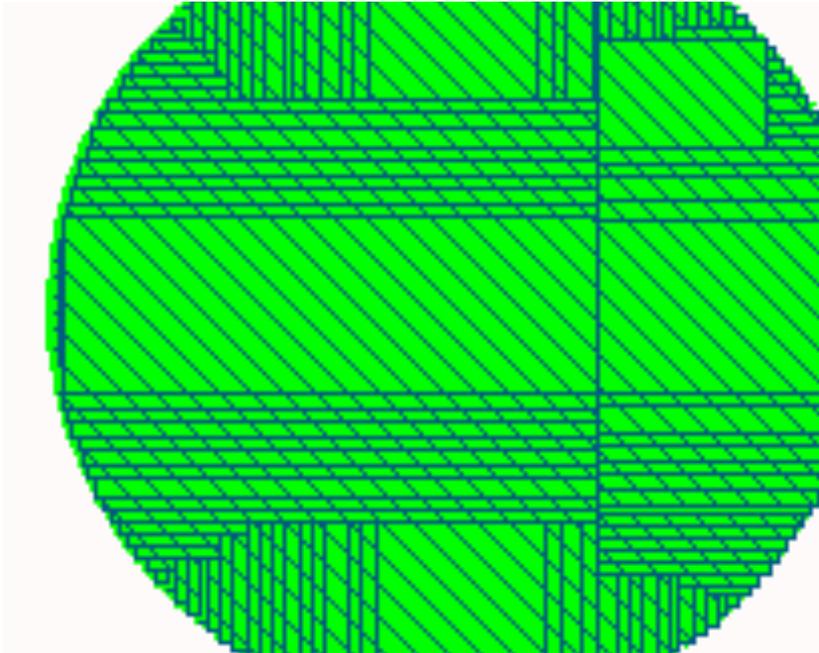


Source: ASML

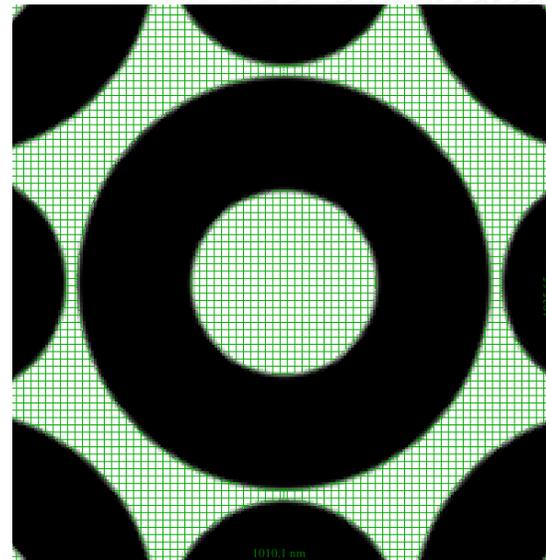
$$\text{Resolution of EUV} = \frac{13.5\text{nm wavelength}}{0.33 \text{ Numerical Aperture}}$$



# Multi-beam Mask Writing Has Enabled Curvy Masks



- Generates too many shots
- Takes too long to write



Multi-beam mask writer

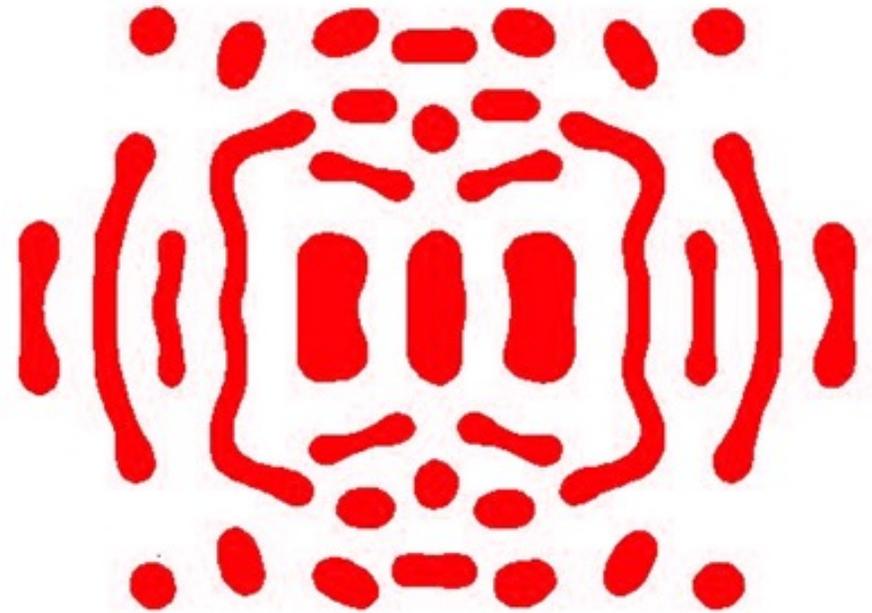
- Designed for curvilinear ILT
- Writes any shape in constant time

# ILT is Software that Computes Mask Shapes

*Generates Curvilinear Masks for Multi-beam Writing*



Design (Wafer Target)



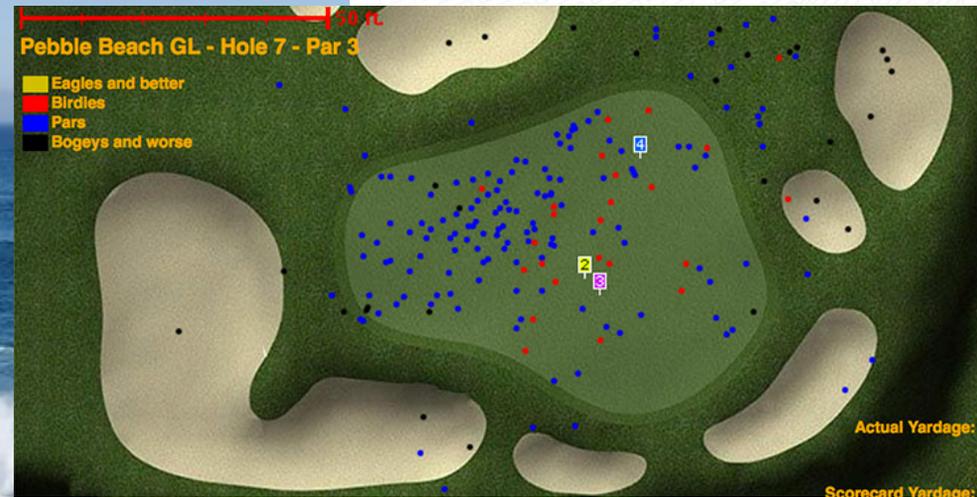
Curvilinear ILT (Mask Target)



# Key to Manufacturing is Resilience to Variation

Shortest hole on PGA Tour is a Difficult Par 3

7<sup>th</sup> Hole Pebble Beach (107-yd, Hard Par 3)

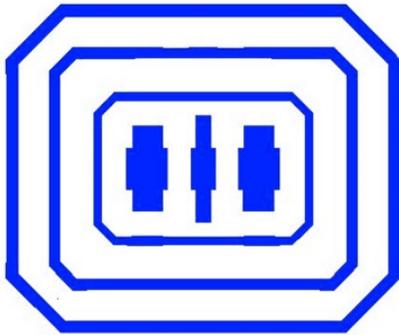


Shot Dispersion of Pros in 2016  
25 birdies; 153 pars; 32 bogeys; 8 Doubles

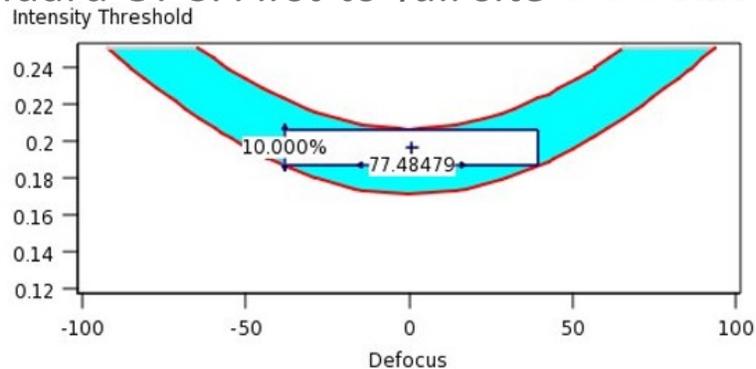
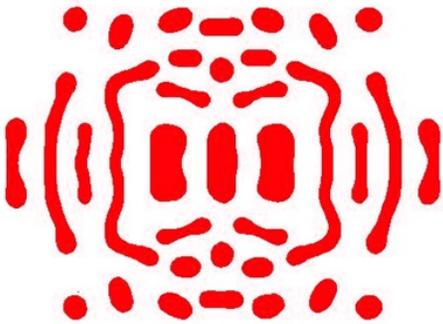
# Curvy Masks: More Resilient to Manufacturing Variation

Curvilinear ILT vs. Standard OPC: *First-to-fail site*

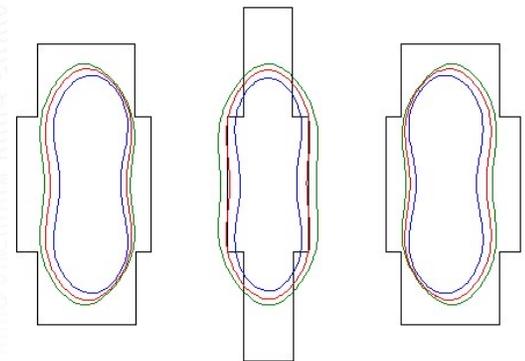
Standard OPC



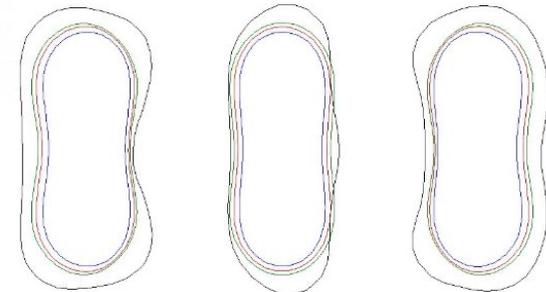
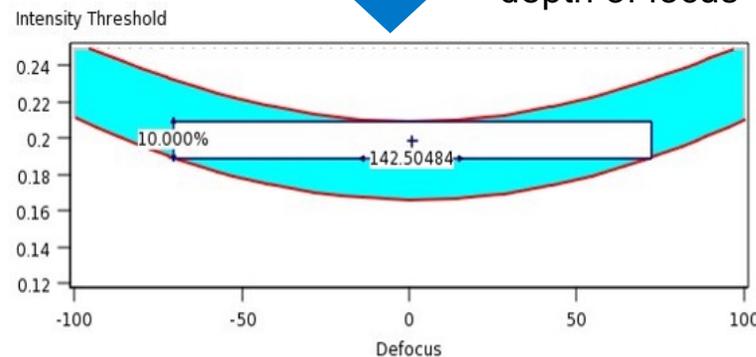
Curvilinear ILT



PV Band  
0, 60, 90nm defocus



~85% increase in depth of focus

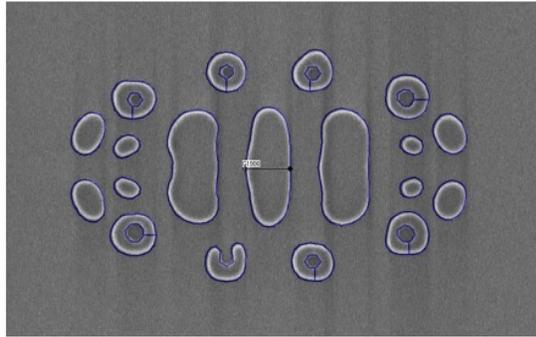
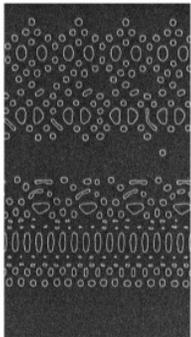


Source: Micron, ILT Curvilinear Mask Designs for Advanced Memory (ebeam.org)



# Manufacturing Now Enables New Choices: Curvilinear Masks Are Here Today

## Micron Shows Curvilinear ILT Mask Written by NuFlare Multi-Beam Writer MBM-1000 with High Pattern Fidelity



Blue outline =  
Mask Data

- Pattern fidelity is not a concern, even with aggressive AFs

- In collaboration with NuFlare and D2S: written on MBM-1000

Overlay of Mask Data and Mask SEM

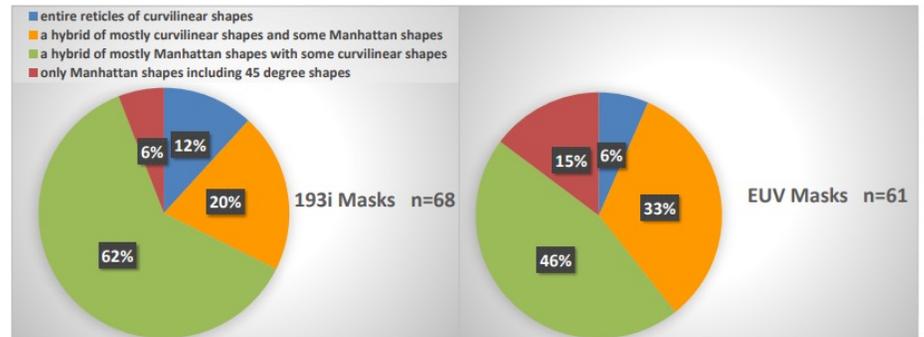


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## Curvilinear Shapes to be Pervasive by 2023 94% of 193i, 85% of EUV masks with some curvilinear shapes



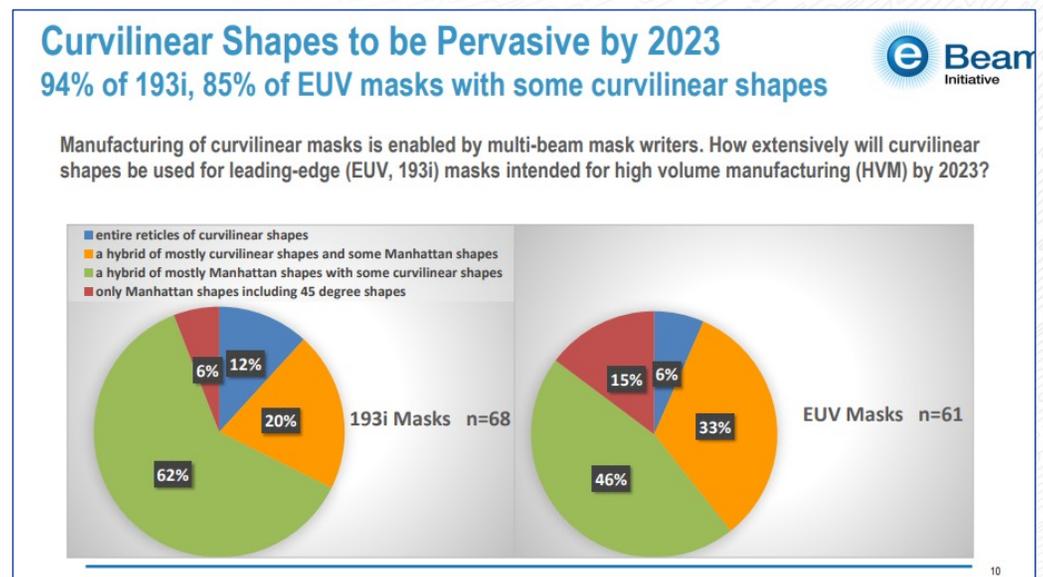
Manufacturing of curvilinear masks is enabled by multi-beam mask writers. How extensively will curvilinear shapes be used for leading-edge (EUV, 193i) masks intended for high volume manufacturing (HVM) by 2023?



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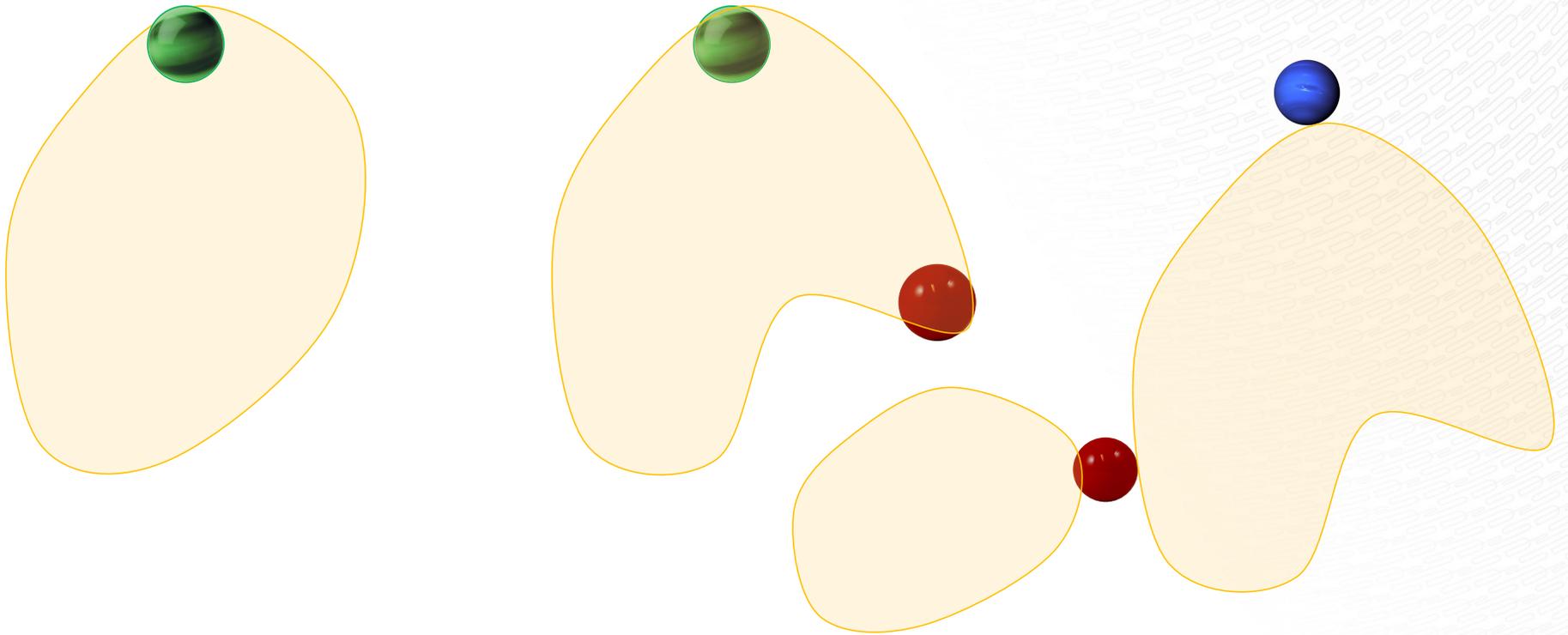
# Both 193i and EUV Will Use Curvy Masks

- Masks are written by data
- Wafers are written by masks
- Curvy masks can be written just as accurately and just as quickly for the same cost:
  - Curvy data format with SEMI
  - Pixel-based GPU-accelerated datapath for:
    - Mask process correction (MPC)
    - Mask rules check (MRC)

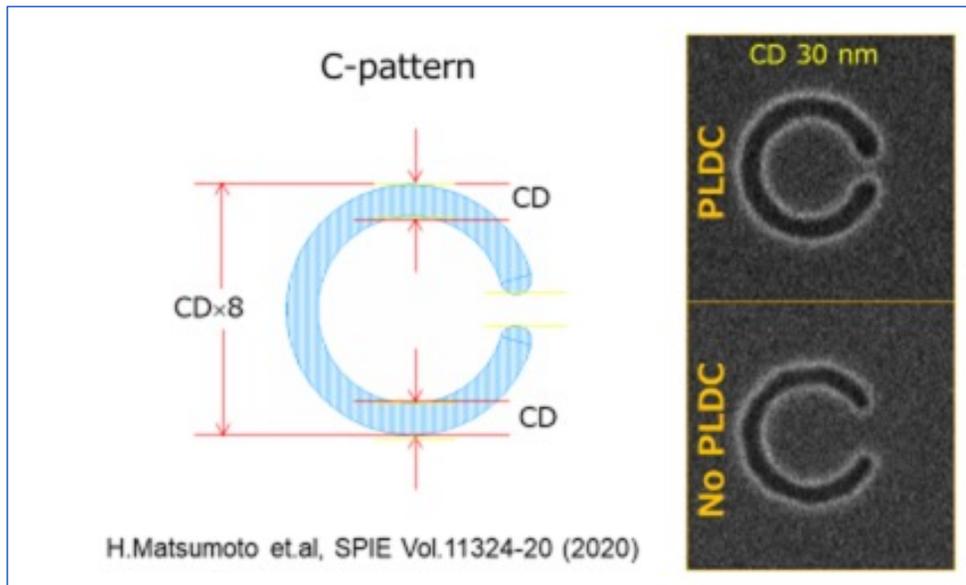


# Manufacturing Has Been Trailblazing:

*Curvy MRC Shows Simplified Curvy DRC is Known-Feasible*

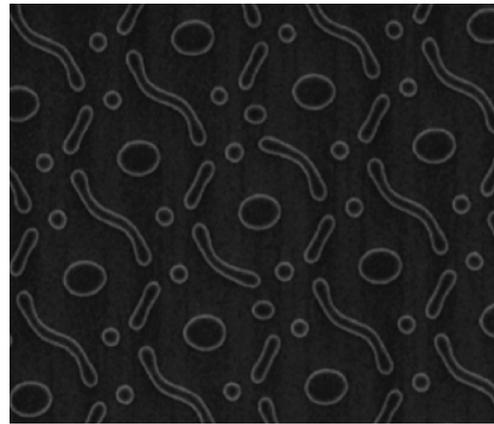


# Manufacturing Has Been Trailblazing: *Mask Process Correction and Bias In Pixel Domain*



- NuFlare's Multi-Beam Mask Writer has:
  - Linearity Correction including for Curvy Masks
  - Edge Enhancement including for Curvy Masks
  - Every pixel enhanced
  - Real time while writing (only possible inline w/GPU)
- For masks, everything is handled flat, too
- So, we know that similar things in the wafer design domain are also feasible

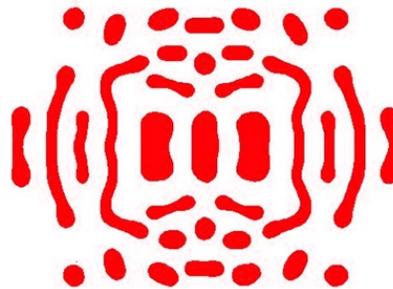
# Manufacturing Has Been Trailblazing: *Curvy Designs (Wafer Targets) can be Manufactured Now*



Multi-beam Mask Writer

Curvy ILT

GPU Acceleration

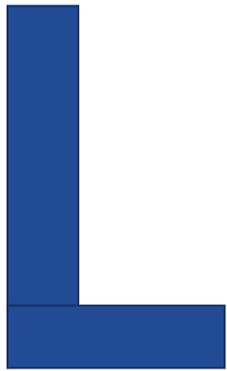


Curvy Masks

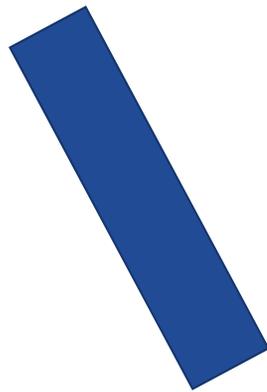


# “Curvy Design” Means Curvy Connections

*Mask Shapes are All Curvilinear*



Manhattan Design



Non-Manhattan Design

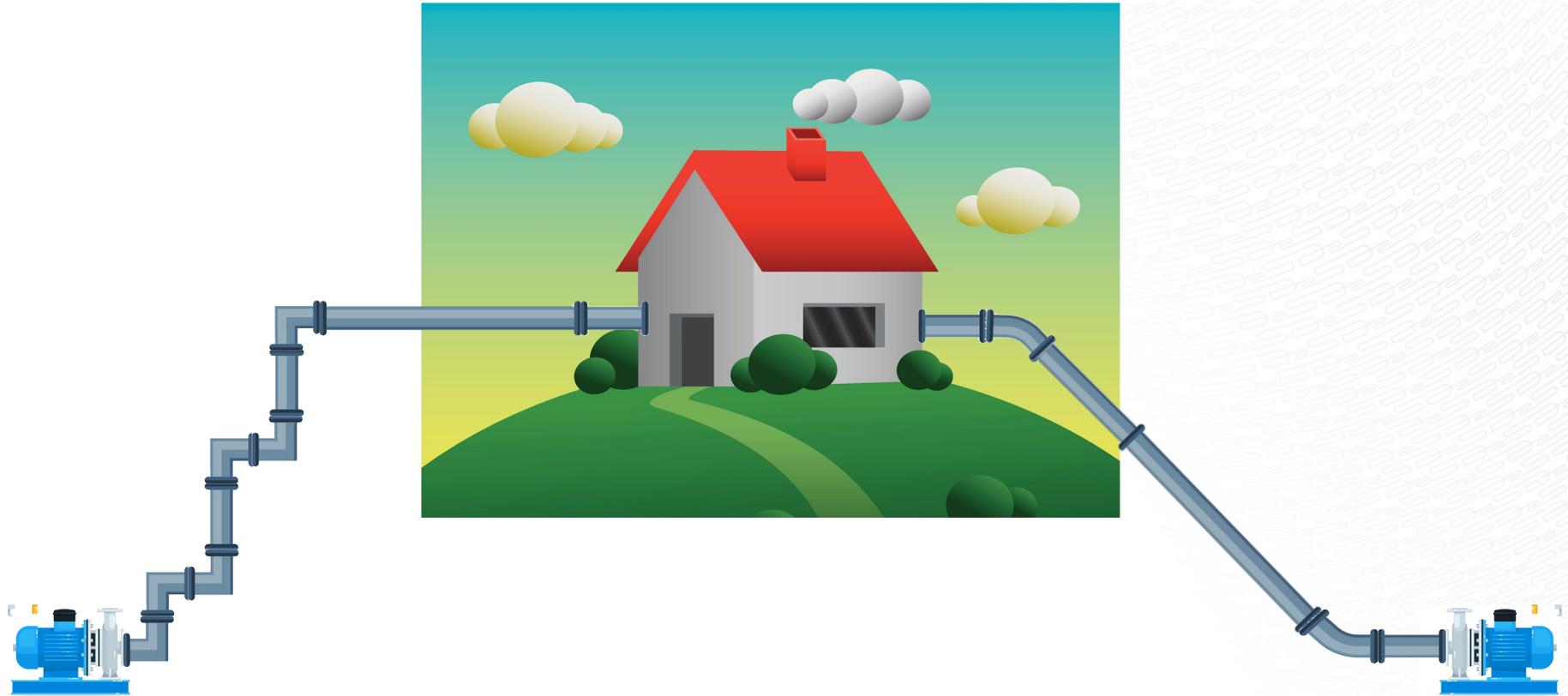


Curvy Design

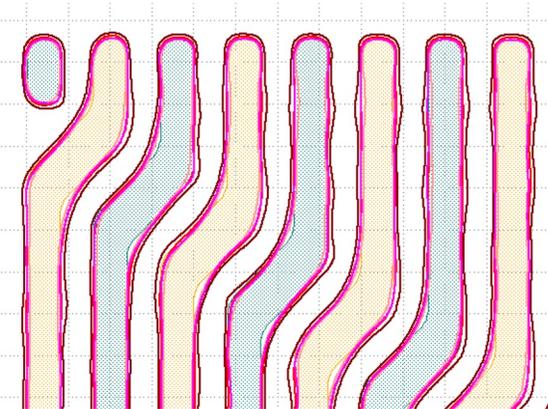
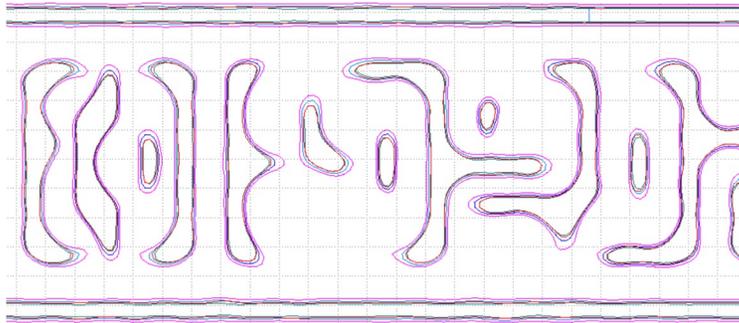


Curvy Design

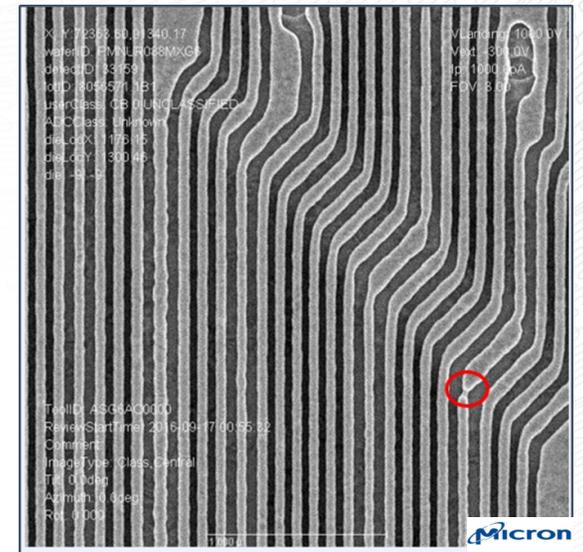
# Intuitively, the Efficiency of Curves Makes Sense



# Curvy Design is Manufacturing-Aware Design



- Knowing what will be manufactured
  - Removes complex design rules
  - Tightens process corners with per-instance parasitic bounds
- Manufacturing target is achievable
- Curvy design is more reliably manufacturable
- Gains in
  - Performance
  - Power
  - Area
  - Yield



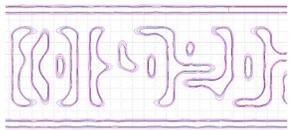
# Could Curvy Routing Substantially Reduce Vias?



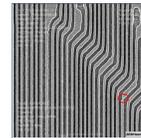
- High-rise buildings have nothing on the first floor but elevator shafts
- Chips have the same problem with vias
- Most chips are interconnect-limited
- Is it time to break the Manhattan assumption?

# Four Things Needed to Enable Curvy Design

*General Perception: "Everything has to Change"*



Custom Design



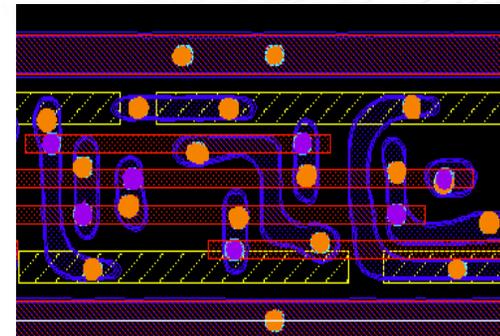
Routing



Parasitic Extraction



DRC



# Imagine DAC 2025...

## Engineering Track: Backend Design: **Early Results in Curvy Design**

1:30-1:45 “Routing without the Manhattan assumption”

1:45-2:00 “Custom layout for curvy shapes”

2:00-2:15 “Fast DRC of curvy designs”

2:15-2:30 “Capacitance extraction of curvy designs”

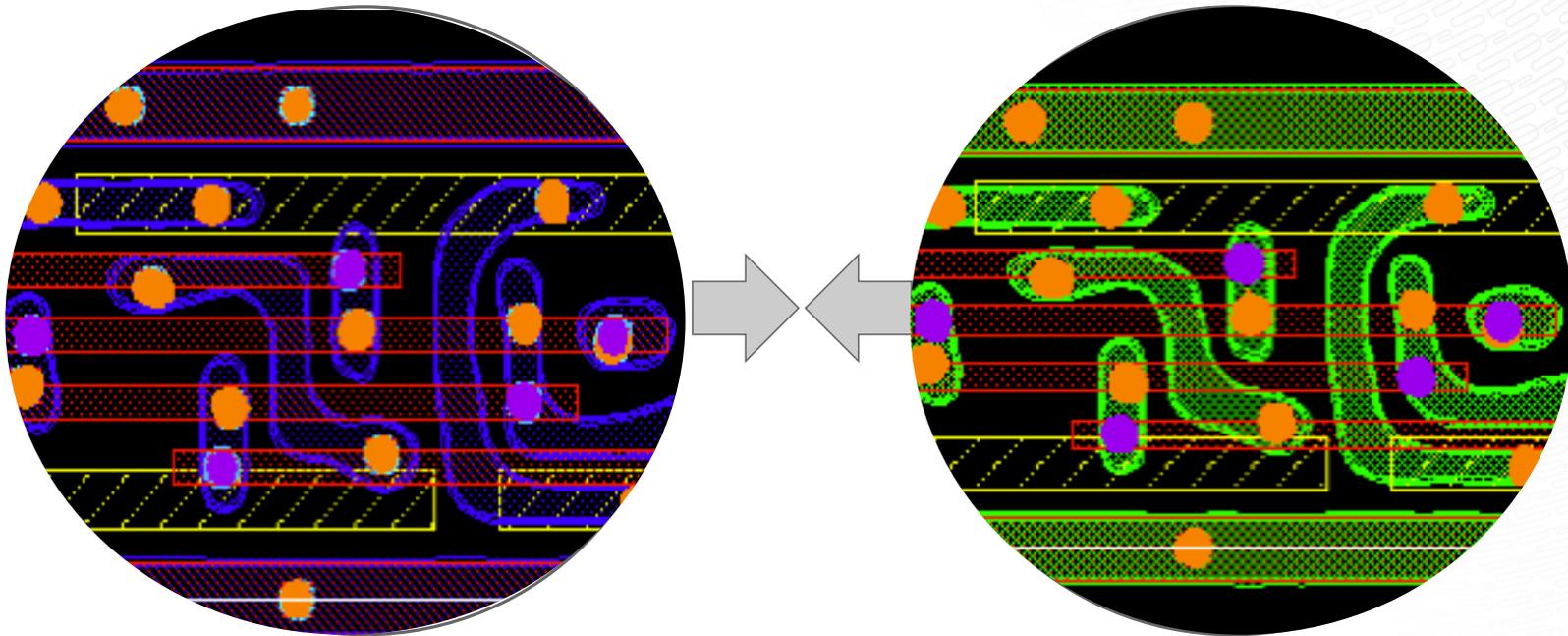
2:30-2:45 “Reducing power using curvy designs”

# Future: Curvy Design Everywhere

*Much Closer to “What You Design is What You Get”*

Design

Manufacturing



DES